Search Notes

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10585733

Applicant(s)/Patent Under Reexamination

ICHIKAWA, TAKESHI

Examiner

SELIM AHMED

Art Unit

2826

SEARCHED

Class	Subclass	Date	Examiner
438	57, 59, 60, 73, 78	11/9/08	/sa/
257	291, 292	11/9/08	/sa/

SEARCH NOTES		
es	Date	Examiner

Search NotesDateExample 1Test search such as, buried channel, surface channel, image sensor,
CMOS sensor, photoelectric, pixel, transistor, substrate and their boolean
combinations were searched.11/9/08/sa/

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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